

CEI AWL681/AWL681M

OPTICAL INSPECTION STATION
WITH INKLESS BINNING FOR 200MM WAFERS

APPLICATIONS:

➔ *Wafer Sorting*

➔ *Optical inspection with Inkless Binning*

FEATURES:

- *Atmospheric robot wafer handling*
- *Capability to handle thin wafer (> 6 mils)*
- *Multi function- Cassette to Cassette Sort , Cassette to XY-stage for micro inspection*
- *Inkless Binning catered to handle all Semi Std Map Format*
- *Macro inspection (Frontside , Backside & Edge defect)*
- *Tilting & Spin Module*
- *Capable to integrate with any OEM Microscope*
- *Optical Character Reader (OCR)*
- *Smallest foot print*
- *SEC II GEM (Option)*
- *Wafer Aligner (Option)*

